Title:Qualification of Cu as an alternate bond wire & die coat for select devicesCustomer Contact:Change Management TeamDept:Quality Services								
Customer Contact: Change Management Team Dept: Ouality Services	Title: Qualification of Cu as an alternate bond wire & die coat for select devices							
Proposed 1 st Ship Date: May 27, 2024 Sample Requests accepted until: March 28	28, 2024*							
*Sample requests received after March 28, 2024 will not be supported.								
Assembly Site Design Wafer Bump Ma								
Assembly Process Data Sheet Wafer Bump Pr								
Assembly Materials Part number change Wafer Fab Site Mechanical Specification Test Site Wafer Fab Materials								
	Wafer Fab Material Wafer Fab Process							
PCN Details								
Description of Change:								
This PCN is to inform of an alternative bond wire & die coat qualification for the device	ces in the							
product affected section as follows:								
Group 1 Devices: Bond wire and die coat change								
What Current Additional	al							
Current Bond wire, DiameterAu, 1.0 milsCu, 0.96 mi	nil							
Die Coat BCB PI								
Group 2 Devices: Bond wire only change								
	Additional							
Current Bond wire, DiameterAu, 0.96 milCu, 1.0 mil	il							
Reason for Change:								
 Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock 								
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / ne	negative):							
None								
Impact on Environmental Ratings								
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.								
RoHS REACH Green Status IEC 62								
No Change No Change No Change No Change	iige							
Changes to product identification resulting from this PCN:								
None								

Product Affected:			
Group 1 Device list:			
LMP8640HVMKX-F/NOPB	LMP8640MKX-H/NOPB	TPL5010DDCR	TPL5110DDCR
LMP8640HVMKX-H/NOPB	LMP8640MKX-T/NOPB	TPL5010DDCT	TPL5110DDCT
LMP8640HVMKX-T/NOPB			
Group 2 Device List			
TPS62162DSGT			

Group 1 Qual Memo:

TI Information Selective Disclosure

Qualification Report

SOT23 6DDC 0.96mil Cu on ABCD150 & CMOS9T DAF+Spincoat Devices Approve Date 05-JANUARY -2024

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: TPL5010DDCR	Qual Device: LMP8640HVMK- <u>F/NOPB</u>	QBS Reference: LMP7711MK/NOPB	QBS Reference: LM4041AIM3X- <u>1.2/NOPB</u>	QBS Reference: LMC7101AIM5/NOPB	QBS Reference: LMV7275MG/NOPB	QBS Reference: LMP8640QMKX- <u>T/NOPB</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	3/231/0	2	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	-	3/231/0
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	1/77/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	3/231/0		-	1/77/0	1/77/0	1/77/0	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-		-	-	3/231/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters		1/30/0	1/30/0	2/60/0	1/30/0	1/30/0	3/90/0	1/30/0

• QBS: Qual By Similarity

Qual Device TPL5010DDCR is qualified at MSL1 260C
 Qual Device LMP8640HVMK-F/NOPB is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2207-052

Group 2 Qual Memo:



Туре	Test Name / Condition	Duration	Qual Device: <u>TPS62172DSGR</u>	QBS Product Reference:	QBS Product Reference:	QBS Package Reference:	QBS Process Reference:		
Type				TPS62162DSGR	TP S62160D SGR	TP \$65680R SN	TPS62110RSA		
	Electrical Characterization	Per							
ED		Datasheet Parameters	-	Pass	Pass	Pass	Pass		
HBM	ESD - HBM	3000 V	-	-	1/3/0	2/6/0	-		
CDM	ESD - CDM	1500 V	-	-	1/3/0	2/6/0	-		
LU	Latch-up	(Per JESD78)	-	-	1/6/0	2/12/0	3/15/0		
HTOL	Life Test, 150C	300 Hours	-	-	-	3/231/0	-		
HTOL	Life Test, 140C	480 Hours	-	-	-	-	3/231/0		
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	-		
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	-	-	3/1881/0		
HTSL	High Temp Storage Bake, 170C	420 Hours	-	-	-	2/154/0	3/231/0		
HTSL	High Temp Storage Bake, 150C	1000 Hours		-	-	1/77/0	-		
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0	3/231/0		
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0	-		
AC	Autoclave 121C	96 Hours	-	-	-	-	3/231/0		
тс	Temperature Cycle, -65/150C	500 Cycles	-	-	-	3/231/0	-		
тс	Temperature Cycle, -55/125C	700 Cycles	-	-	-	-	3/231/0		
FTY	Final Test Yield	-	Pass	-	-	-	-		
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	-	-	-		
	al <u>By</u> Similarity								
. Quel Device TPS82172DSGR is qualified at MSL2 280C									

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Qual Device TPS82172DSGR is qualified at MSL2 280C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2202-061

For questions regarding this notice, e-mails can be sent to Change Management team or your local Field Sales Representative.

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